

Application/Control No.	Applicant(s)/Patent under Reexamination	er
10/814,971	AGARWAL ET AL.	
Examiner	Art Unit	
David Ruttner	1712	

SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
524	all	5/1/2007	DB	
525	all	5/1/2007	DB	
		1		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
east	5/1/2007	DB	